

Sensor test idea at Hiroshima University

- Goals: Studying the temperature dependence of sensor performance
 - Feedback to establish calibration method and support structure and PCB designs
- Peltier device fits to control temperature
 - Fine temperature control
 - applicable not only lab tests but also beam tests
- Mimic the ASIC effects on the sensor
 - Peltier device can be placed in the same location as the ASIC to mimic temperatures to reproduce conditions similar to the real thing
- Hiroshima University already built the test bench system with radiation source
 - Need to purchase the Peltier device and its control system
- Budget request:
 - Peltier device and its control system: \$3,000~5,000
 - Trip for beam test at U.S. or EU (e.g. FNAL or CERN): 2 times 2weeks each = \$25,000

